BUK7675-100A

N-channel TrenchMOS standard level FET

Rev. 02 — 31 July 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

- Suitable for standard level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V, 24 V and 42 V loads
- Automotive and general purpose power switching
- Motors, lamps and solenoids

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	100	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 1</u> and <u>3</u>	-	-	23	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	99	W
Avalanc	he ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 14 A; $V_{sup} \le$ 100 V; R_{GS} = 50 Ω ; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-	-	100	mJ
Static ch	naracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 13 \text{ A};$ $T_j = 175 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{\text{and } 13}$	-	-	187	mΩ
		V_{GS} = 10 V; I_D = 13 A; T_j = 25 °C; see <u>Figure 12</u> and <u>13</u>	-	64	75	mΩ



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Pinning information

Table 2. **Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		$G \longrightarrow A$
mb	D	mounting base; connected to drain		mbb076 S
			SOT404 (D2PAK)	

Ordering information

Table 3. **Ordering information**

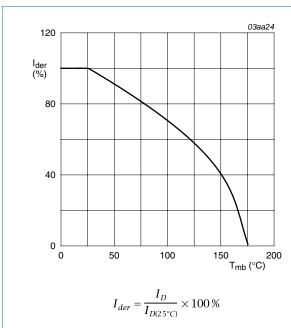
Type number	Package		
	Name	Description	Version
BUK7675-100A	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

Limiting values

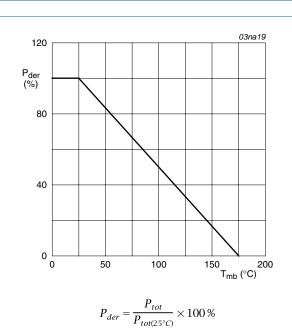
Table 4. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	100	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	100	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> and <u>3</u>	-	23	Α
		T _{mb} = 100 °C; V _{GS} = 10 V; see <u>Figure 1</u>	-	16.2	Α
I_{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \mu s$; pulsed; see <u>Figure 3</u>	-	92	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	99	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 14 A; $V_{sup} \le$ 100 V; R_{GS} = 50 Ω ; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-	100	mJ
Source-dr	ain diode				
Is	source current	T _{mb} = 25 °C	-	23	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	92	Α

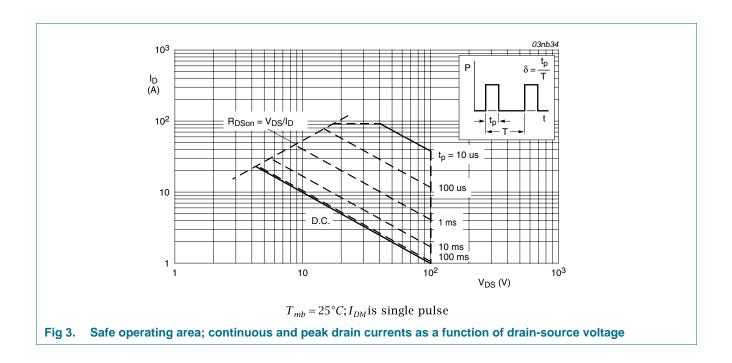


Normalized continuous drain current as a function of mounting base temperature



Normalized total power dissipation as a function of mounting base temperature

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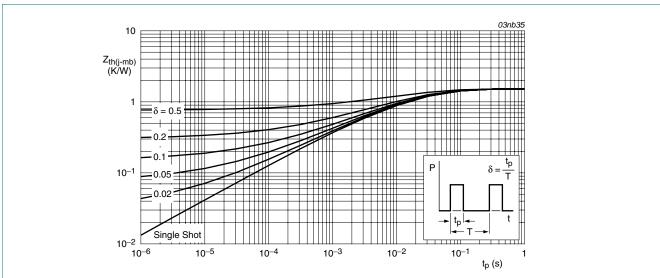


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Thermal characteristics

Thermal characteristics Table 5.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	-	1.5	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient		-	50	-	K/W

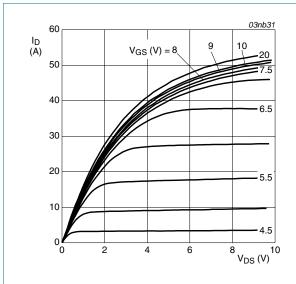


Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

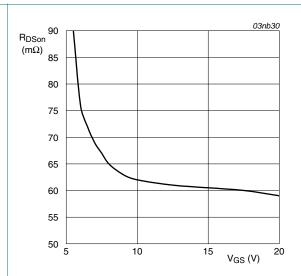
Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V _{(BR)DSS} drain-source breakdown vo		$I_D = 0.25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	100	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	89	-	-	V
V _{GS(th)}	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 175 °C; see <u>Figure 11</u>	1	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 11</u>	-	-	4.4	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 11</u>	2	3	4	V
I _{DSS}	drain leakage current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
		$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.05	10	μΑ
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 20 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{DS} = 0 \text{ V}; V_{GS} = -20 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_{D} = 13 A; T_{j} = 175 °C; see <u>Figure 12</u> and <u>13</u>	-	-	187	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 13 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 12 and 13	-	64	75	mΩ
Dynamic	characteristics					
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	907	1210	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 15</u>	-	127	150	pF
C _{rss}	reverse transfer capacitance		-	78	110	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 2.2 \Omega; V_{GS} = 10 \text{ V};$	-	8	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega$; $T_j = 25 °C$	-	39	-	ns
d(off)	turn-off delay time		-	26	-	ns
t _f	fall time		-	24	-	ns
L _D	internal drain inductance	from drain lead 6 mm from package to centre of die; $T_j = 25$ °C	-	4.5	-	nΗ
		from upper edge of drain mounting base to centre of die; $T_j = 25$ °C	-	2.5	-	nΗ
Ls	internal source inductance	from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 14	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 13 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = -10 \text{ V}$;	-	64	-	ns
Q_r	recovered charge	$V_{DS} = 30 \text{ V}; T_i = 25 \text{ °C}$		120	-	nC



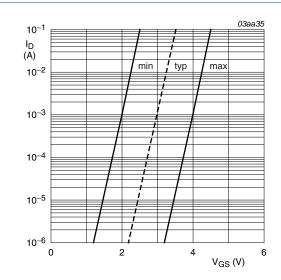
 $T_j = 25$ °C; $t_p = 300 \mu s$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



$$T_j = 25^{\circ}C; I_D = 10A$$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $T_i = 25 \,^{\circ}C; V_{DS} = 5V$

Sub-threshold drain current as a function of gate-source voltage

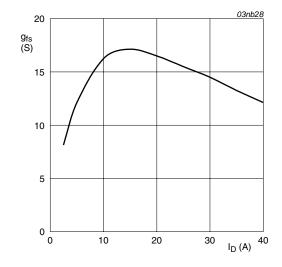


Fig 8. Forward transconductance as a function of drain current; typical values

 $T_i = 25^{\circ}C; V_{DS} = 25V$

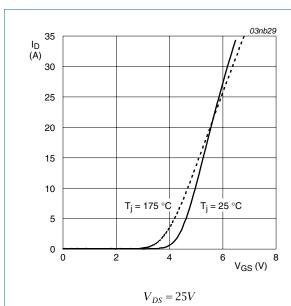
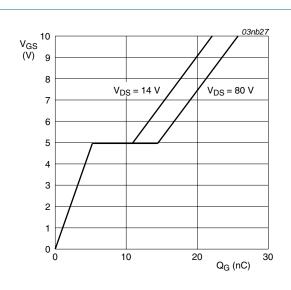


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j = 25^{\circ}C; I_D = 25A$

Fig 10. Gate-source voltage as a function of turn-on gate charge; typical values

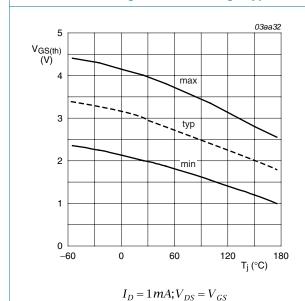


Fig 11. Gate-source threshold voltage as a function of junction temperature

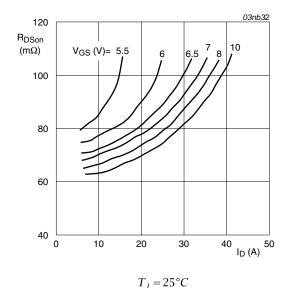


Fig 12. Drain-source on-state resistance as a function of drain current; typical values

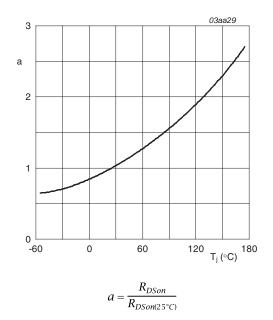
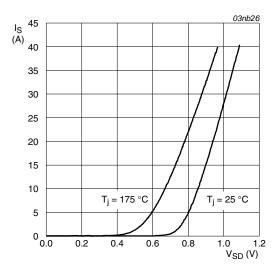


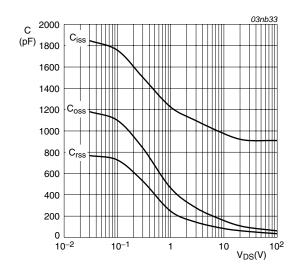
Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature



 $V_{GS} = 0V$

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Fig 14. Reverse diode current as a function of reverse diode voltage; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

7. Package outline

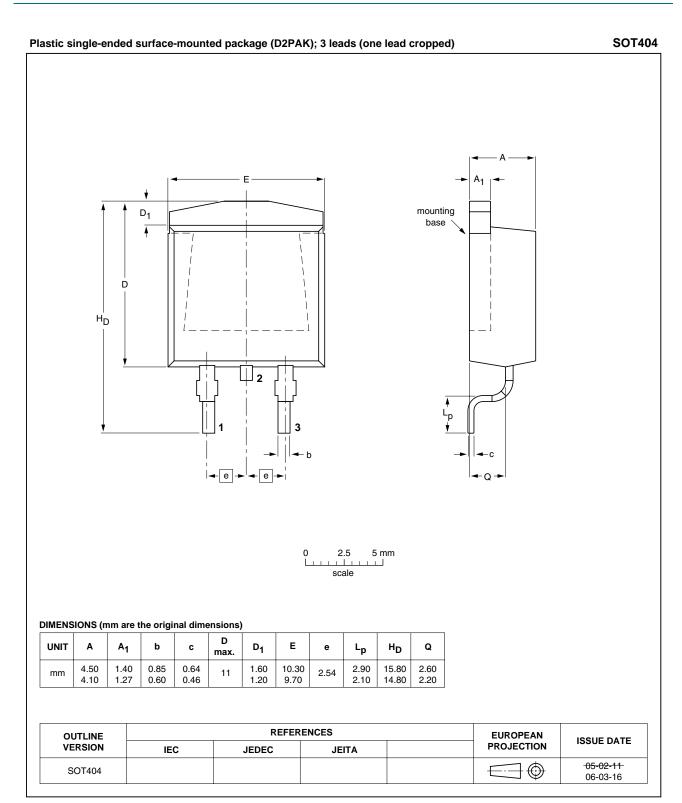


Fig 16. Package outline SOT404 (D2PAK)

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Revision history

Table 7. **Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7675-100A_2	20090731	Product data sheet	-	BUK7575_7675-100A-01
Modifications:	guidelines o	of this data sheet has been of NXP Semiconductors. have been adapted to the		·
	•	er BUK7675-100A separat		• • •
BUK7575_7675-100A-01 (9397 750 07623)	20001024	Product specification	-	-

Legal information

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Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design. [1]
- The term 'short data sheet' is explained in section "Definitions".
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